

10073830 CLS

Most Frequently Occurring Classifications of Patents Returned  
From A Search of 10073830 on June 30, 2004

Original Classifications

11 714/727  
6 714/726  
3 324/158.1  
3 714/724  
2 324/763  
2 326/38  
2 703/14  
2 714/731  
2 714/733  
2 717/139

Cross-Reference Classifications

9 714/727  
7 714/724  
4 714/30  
4 714/731  
4 714/733  
3 324/158.1  
3 714/725  
3 714/726  
3 716/4  
2 326/40  
2 326/41  
2 326/46  
2 703/13  
2 714/42  
2 714/734  
2 716/1  
2 716/16  
2 716/17

Combined Classifications

20 714/727  
10 714/724  
9 714/726  
6 324/158.1  
6 714/731  
6 714/733  
5 714/30  
3 326/38  
3 703/14  
3 714/725  
3 716/16

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3 716/4  
2 324/763  
2 326/39  
2 326/40  
2 326/41  
2 326/46  
2 327/202  
2 365/201  
2 703/13  
2 714/42  
2 714/734  
2 716/1  
2 716/17  
2 717/139

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Titles of Most Frequently Occurring Classifications of Patents Returned

From A Search of 10073830 on June 30, 2004

- 20 714/727 (11 OR, 9 XR)  
Class 714 : ERROR DETECTION/CORRECTION AND FAULT  
DETECTION/RECOVERY  
714/699 PULSE OR DATA ERROR HANDLING  
714/724 .Digital logic testing  
714/726 ..Scan path testing (e.g., level sensitive sca  
n  
design (LSSD))  
714/727 ...Boundary scan
- 10 714/724 (3 OR, 7 XR)  
Class 714 : ERROR DETECTION/CORRECTION AND FAULT  
DETECTION/RECOVERY  
714/699 PULSE OR DATA ERROR HANDLING  
714/724 .Digital logic testing
- 9 714/726 (6 OR, 3 XR)  
Class 714 : ERROR DETECTION/CORRECTION AND FAULT  
DETECTION/RECOVERY  
714/699 PULSE OR DATA ERROR HANDLING  
714/724 .Digital logic testing  
714/726 ..Scan path testing (e.g., level sensitive sca  
n  
design (LSSD))
- 6 324/158.1 (3 OR, 3 XR)  
Class 324 : ELECTRICITY: MEASURING AND TESTING  
324/158.1 MISCELLANEOUS
- 6 714/731 (2 OR, 4 XR)  
Class 714 : ERROR DETECTION/CORRECTION AND FAULT  
DETECTION/RECOVERY  
714/699 PULSE OR DATA ERROR HANDLING  
714/724 .Digital logic testing  
714/726 ..Scan path testing (e.g., level sensitive sca  
n  
design (LSSD))  
714/731 ...Clock or synchronization
- 6 714/733 (2 OR, 4 XR)  
Class 714 : ERROR DETECTION/CORRECTION AND FAULT  
DETECTION/RECOVERY  
714/699 PULSE OR DATA ERROR HANDLING

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714/724 .Digital logic testing  
714/733 ..Built-in testing circuit (BILBO)

5 714/30 (1 OR, 4 XR)  
Class 714 : ERROR DETECTION/CORRECTION AND FAULT  
DETECTION/RECOVERY  
714/100 DATA PROCESSING SYSTEM ERROR OR FAULT HANDLING

714/1 .Reliability and availability  
714/25 ..Fault locating (i.e., diagnosis or testing)

714/27 ...Particular access structure  
714/30 ....Built-in hardware for diagnosing or testin  
g  
or test mode  
within-system component (e.g., microprocess  
circuit, scan path)

3 326/38 (2 OR, 1 XR)  
Class 326 : ELECTRONIC DIGITAL LOGIC CIRCUITRY  
326/37 MULTIFUNCTIONAL OR PROGRAMMABLE (E.G.,  
UNIVERSAL, ETC.)  
326/38 .Having details of setting or programming of  
interconnections or logic functions

3 703/14 (2 OR, 1 XR)  
Class 703 : DATA PROCESSING: STRUCTURAL DESIGN,  
MODELING, SIMULATION, AND EMULATION  
703/13 SIMULATING ELECTRONIC DEVICE OR ELECTRICAL  
SYSTEM  
703/14 .Circuit simulation

3 714/725 (0 OR, 3 XR)  
Class 714 : ERROR DETECTION/CORRECTION AND FAULT  
DETECTION/RECOVERY  
714/699 PULSE OR DATA ERROR HANDLING  
714/724 .Digital logic testing  
714/725 ..Programmable logic array (PLA) testing

3 716/16 (1 OR, 2 XR)  
Class 716 : DATA PROCESSING: DESIGN AND ANALYSIS OF  
CIRCUIT OR SEMICONDUCTOR MASK  
716/1 CIRCUIT DESIGN  
716/12 .Routing (e.g., routing map, netlisting)  
716/16 ..PLA, PLD, FPGA, OR MCM

3 716/4 (0 OR, 3 XR)  
Class 716 : DATA PROCESSING: DESIGN AND ANALYSIS OF

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CIRCUIT OR SEMICONDUCTOR MASK

716/1 CIRCUIT DESIGN  
716/4 .Testing or evaluating

2 324/763 (2 OR, 0 XR)  
 Class 324 : ELECTRICITY: MEASURING AND TESTING  
 324/500 FAULT DETECTING IN ELECTRIC CIRCUITS AND OF  
           ELECTRIC COMPONENTS  
 324/537 .Of individual circuit component or element  
 324/763 ..DUT including test circuit

2 326/39 (1 OR, 1 XR)  
 Class 326 : ELECTRONIC DIGITAL LOGIC CIRCUITRY  
 326/37 MULTIFUNCTIONAL OR PROGRAMMABLE (E.G.,  
           UNIVERSAL, ETC.)  
 326/39 .Array (e.g., PLA, PAL, PLD, etc.)

2 326/40 (0 OR, 2 XR)  
 Class 326 : ELECTRONIC DIGITAL LOGIC CIRCUITRY  
 326/37 MULTIFUNCTIONAL OR PROGRAMMABLE (E.G.,  
           UNIVERSAL, ETC.)  
 326/39 .Array (e.g., PLA, PAL, PLD, etc.)  
 326/40 ..With flip-flop or sequential device

2 326/41 (0 OR, 2 XR)  
 Class 326 : ELECTRONIC DIGITAL LOGIC CIRCUITRY  
 326/37 MULTIFUNCTIONAL OR PROGRAMMABLE (E.G.,  
           UNIVERSAL, ETC.)  
 326/39 .Array (e.g., PLA, PAL, PLD, etc.)  
 326/41 ..Significant integrated structure, layout, or  
           layout interconnections

2 326/46 (0 OR, 2 XR)  
 Class 326 : ELECTRONIC DIGITAL LOGIC CIRCUITRY  
 326/37 MULTIFUNCTIONAL OR PROGRAMMABLE (E.G.,  
           UNIVERSAL, ETC.)  
 326/46 .Sequential (i.e., finite state machine) or  
           with flip-flop

2 327/202 (1 OR, 1 XR)  
 Class 327 : MISCELLANEOUS ACTIVE ELECTRICAL NONLINEAR  
           DEVICES, CIRCUITS, AND SYSTEMS  
 327/100 SIGNAL CONVERTING, SHAPING, OR GENERATING  
 327/185 .Particular stable state circuit (e.g.,  
           tristable, etc.)  
 327/199 ..Circuit having only two stable states (i.e.,  
           bistable)  
 327/202 ...Master-slave bistable latch

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2 365/201 (1 OR, 1 XR)  
Class 365 : STATIC INFORMATION STORAGE AND RETRIEVAL  
365/189.01 READ/WRITE CIRCUIT  
365/201 .Testing

2 703/13 (0 OR, 2 XR)  
Class 703 : DATA PROCESSING: STRUCTURAL DESIGN,  
MODELING, SIMULATION, AND EMULATION  
703/13 SIMULATING ELECTRONIC DEVICE OR ELECTRICAL  
SYSTEM

2 714/42 (0 OR, 2 XR)  
Class 714 : ERROR DETECTION/CORRECTION AND FAULT  
DETECTION/RECOVERY  
714/100 DATA PROCESSING SYSTEM ERROR OR FAULT HANDLING  
  
714/1 .Reliability and availability  
714/25 ..Fault locating (i.e., diagnosis or testing)  
  
714/40 ...Component dependent technique  
714/42 ....Memory or storage device component fault

2 714/734 (0 OR, 2 XR)  
Class 714 : ERROR DETECTION/CORRECTION AND FAULT  
DETECTION/RECOVERY  
714/699 PULSE OR DATA ERROR HANDLING  
714/724 .Digital logic testing  
714/734 ..Structural (in-circuit test)

2 716/1 (0 OR, 2 XR)  
Class 716 : DATA PROCESSING: DESIGN AND ANALYSIS OF  
CIRCUIT OR SEMICONDUCTOR MASK  
716/1 CIRCUIT DESIGN

2 716/17 (0 OR, 2 XR)  
Class 716 : DATA PROCESSING: DESIGN AND ANALYSIS OF  
CIRCUIT OR SEMICONDUCTOR MASK  
716/1 CIRCUIT DESIGN  
716/17 .Programmable integrated circuit (e.g., basic  
cell, standard cell, macrocell)

2 717/139 (2 OR, 0 XR)  
Class 717 : DATA PROCESSING: SOFTWARE DEVELOPMENT,  
INSTALLATION, AND MANAGEMENT  
717/100 SOFTWARE PROGRAM DEVELOPMENT TOOL (E.G.,  
INTEGRATED CASE TOOL OR STAND-ALONE DEVELOPMENT  
TOOL)

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717/136 .Translation of code  
717/139 ..Interpreter

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PLUS Search Results for S/N 10073830, Searched June 30, 2004

The Patent Linguistics Utility System (PLUS) is a USPTO automated search system for U.S. Patents from 1971 to the present. PLUS is a query-by-example search system which produces a list of patents that are most closely related linguistically to the application searched. This search was prepared by the staff of the Scientific and Technical Information Center, SIRA.

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5898776  
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5510704  
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5477545 62